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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/769,245	01/30/2004	Hsin-Hsien Lu	67,200-1192	8175
75	90 02/07/2006		EXAM	INER
TUNG & ASSOCIATES			KORNAKOV, MICHAIL	
Suite 120 838 W. Long Lake Road			ART UNIT	PAPER NUMBER
Bloomfield Hills, MI 48302			1746	

DATE MAILED: 02/07/2006

Please find below and/or attached an Office communication concerning this application or proceeding.

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	Application No.	on No. Applicant(s)			
	10/769,245	LU ET AL.			
Office Action Summary	Examiner	Art Unit			
	Mlkhail Kornakov	1746			
The MAILING DATE of this communication appears on the cover sheet with the correspondence address Period for Reply					
A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication. - If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication. - Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).					
Status					
1) ☐ Responsive to communication(s) filed on 15 November 2005. 2a) ☐ This action is FINAL . 2b) ☐ This action is non-final. 3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under Ex parte Quayle, 1935 C.D. 11, 453 O.G. 213.					
Disposition of Claims					
4) Claim(s) 1-3,5,11-13,15,16 and 21-30 is/are pending in the application. 4a) Of the above claim(s) is/are withdrawn from consideration. 5) Claim(s) is/are allowed. 6) Claim(s) 1-3,5,11-13,15,16 and 21-30 is/are rejected. 7) Claim(s) is/are objected to. 8) Claim(s) are subject to restriction and/or election requirement.					
Application Papers					
9) The specification is objected to by the Examiner. 10) The drawing(s) filed on is/are: a) accepted or b) objected to by the Examiner. Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a). Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d). 11) The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.					
Priority under 35 U.S.C. § 119					
 12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a) All b) Some * c) None of: 1. Certified copies of the priority documents have been received. 2. Certified copies of the priority documents have been received in Application No 3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)). * See the attached detailed Office action for a list of the certified copies not received. 					
Attachment(s) 1)	4) 🔲 Interview Summary	r (PTO-413)			
2) Notice of Preferences Office (170-032) 2) Notice of Draftsperson's Patent Drawing Review (PTO-948) 3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) Paper No(s)/Mail Date	Paper No(s)/Mail Da				

Application/Control Number: 10/769,245 Page 2

Art Unit: 1746

DETAILED ACTION

1. Claims 1-3, 5,11-13, 15, 16 are amended. Claims 4,6,7,9,10,14,17-20 are cancelled. New claims 21-30 are added by Applicants' amendment of 11/15/2005.

- 2. The text of those sections of Title 35, U.S. Code not included in this action can be found in a prior Office action.
- 3. Claims 1, 2, 5, 21, 22, 23, 24, 25 rejected under 35 U.S.C. 102(e) as being anticipated by Korthius et al (US 2004/0074518).

Korthius discloses a method of cleaning semiconductor wafer having a metal, such as copper on the surface (0048, 0049), the process includes at least two CMP procedures, wherein after the first CMP process, the wafer is rinsed with surfactant (0047). By the virtue of surfactant action, the surface of the wafer inherently acquires hydrophilicity. A third CMP process may be performed, wherein the barrier layer comprising nitride (0050) is removed, Than the spraying of surfactant is performed, and the deionized water rinse is completed (0050). The method includes polishing of a surface of the semiconductor wafer that includes low-K dielectric material (0056)

4. Claims 3, 8,11-13, 15, 16, and 26-30 are rejected under 35 U.S.C. 103(a) as being unpatentable over Korthius in view of Bessho et al (U.S. 6,440,856).

Korthius discloses the invention as claimed as discussed above. Korthius discloses the use of surfactant, however does not specifically provide for the presence of alcohol in the surfactant solution.

Bessho discloses a method for cleaning a wafer surface after the CPM (abstract), the wafer has a layer of dielectric, interlayer insulation and metallic wiring (col.11, lines

Application/Control Number: 10/769,245 Page 3

Art Unit: 1746

20-24). The process of Bessho includes the use of cleaning solution comprising surfactant, wherein the specific and preferred cleaning solution comprises alcohol, such as octanol (C8) (col.9, line 23), wherein the alcohol is used in the amounts of 0.01-5% by weight (col.10, lines 24,25). Bessho also discloses the use of adducts of ethylene oxide in the cleaning composition comprising surfactant and alcohol (example 20 in col.16). Bessho emphasizes that the cleaning solution comprising surfactant can be used before and after CMP. Bessho emphasizes that the use of alcohols is needed for imparting hydrophilicity to the surface to be cleaned. Therefore it would have been obvious to those skilled in the art to include the alcohol into surfactant solution of Korthius, since by the virtue of having OH groups capable of forming hydrogen bonding, such alcohol will impart the hydrophilicity to the wafer surface and thus increase the effectiveness of cleaning. The CMP process that includes polishing of copper, nitride, oxide or low-k material is discussed in the primary reference, as applied above.

Response to Arguments

- 5. Applicant's arguments with respect to claims 1-3, 5,11-13, 15, 16 and 21-30 have been considered but are moot in view of the new ground(s) of rejection.
- 6. However, even thought the reference to Lu is removed from the scope of rejection due to Applicants' amendment, the ONLY thing that is not disclosed by Lu, is the wafer having dielectric or metal layers as presently amended by Applicants. All the other limitations, including plurality of CMP steps and the use of surfactant solution

Application/Control Number: 10/769,245

Art Unit: 1746

comprising C4-C8 alcohol, contrary to Applicants' allegations, are expressly taught by Lu.

7. Applicant's amendment necessitated the new ground(s) of rejection presented in this Office action. Accordingly, **THIS ACTION IS MADE FINAL**. See MPEP § 706.07(a). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to MIkhail Kornakov whose telephone number is (571) 272-1303. The examiner can normally be reached on 9:00 - 5:30.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Michael Barr can be reached on (571) 271-1114. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Application/Control Number: 10/769,245

Art Unit: 1746

Page 5

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

M. (Copnarco)

MIkhail Kornakov Primary Examiner Art Unit 1746

February 4, 2006